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CCS H83;L90

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 20844-2002

Test method for microzone homogeneity of semi-insulating monocrystal gallium arsenide

决绝缘砷化镓单晶微区均匀性测试方法

(English Translation)

Issued on: October 30, 2002 **Implemented on: March 1, 2003**

Issued by: Ministry of Industry and Information Technology

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1 Foreword

SJ 20844-2002 was issued by Ministry of Industry and Information Technology on 30 October 2002 and has been in force since 1 March 2003.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 9 pages in English translation.

2 Scope Preview

This standard specifies the semi-insulating GaAs wafer resistivity, carbon concentration, EL2 concentration and uniformity of micro- PL spectra measurement method. This standard applies to semi-insulating GaAs wafer resistivity, carbon concentration, EL2 concentration and micro- PL spectra Determination of uniformity.

SJ 20844-2002 is filed under Chinese Standard Classification H83;L90, in the field of metallurgy.

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This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 9 pages (approximate)

Chinese original: about 13,117 characters

4 Related standards

Standards on related subjects:

GB/T 25074-2017 - Solar-grade polycrystalline silicon

SJ/T 11488-2015 - Test method for measuring resistivity, hall coefficient and determining hall mobility in semi-insulating GaAs single crystals

YS/T 13-2015 - High pure germanium tetrachloride

SJ 21589-2021 - Indium Phosphide Ingot Rolling Technology Requirements

SJ 21588-2021 - Indium Phosphide Crystal Ingot Cutting and Orientation Technology Requirements

5 Classification and status

Chinese Standard Classification (CCS): H 83; L 90

Prefix SJ: mandatory standard.

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